

Supplementary Information

**Increased hole mobility in anti-ThCr₂Si₂-type La₂O₂Bi co-sintered with
alkaline earth metal oxides for oxygen intercalation and hole carrier
doping**

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Table S1 Crystal structural parameters for $\text{La}_2\text{O}_x\text{Bi}$ with different nominal composition (R_{wp} : R -factor, R_e : expected R -factor, S : goodness-of-fit indicator).

$\text{La}_2\text{O}_x\text{Bi}$	$x = 1.0$	$x = 1.1$	$x = 1.2$	$x = 1.3$	$x = 1.4$	$x = 1.5$	$x = 1.6$	$x = 1.7$	$x = 1.8$	$x = 1.9$	$x = 2.0$
Phase	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$	$\text{La}_2\text{O}_2\text{Bi}$
Space group	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$	$I4/mmm$
a (Å)	4.1064(2)	4.1004(1)	4.0930(1)	4.0895(2)	4.0860(1)	4.0871(1)	4.0845(1)	4.0844(2)	4.0850(1)	4.0867(1)	4.0885(1)
c (Å)	13.4018(12)	13.5187(7)	13.6298(7)	13.7177(9)	13.7612(5)	13.8370(6)	13.9698(6)	13.9800(10)	13.9856(6)	13.9911(7)	13.9953(8)
c/a	3.2636	3.2969	3.33	3.3543	3.3679	3.3855	3.4203	3.4223	3.4236	3.4236	3.4231
$\text{La}_2\text{O}_2\text{Bi}$ (mol%)	51.1	76.8	86.3	89.6	100	100	100	67.9	77.2	54	42.4
LaBi (mol%)	23.8	15.9	13.7	10.4	0	0	0	0	0	0	0
La_2Bi (mol%)	25	7.3	0	0	0	0	0	0	0	0	0
La_2O_3 (mol%)	0	0	0	0	0	0	0	32.1	22.8	46	47.6
R_{wp}	2.358	2.323	2.133	1.736	1.647	1.672	1.742	1.589	1.684	2.025	2.282
R_e	1.401	1.445	1.44	1.436	1.46	1.449	1.407	1.43	1.411	1.781	1.797
S	1.6832	1.6073	1.4809	1.2087	1.1278	1.1545	1.2379	1.114	1.1935	1.2929	1.2694

Table S2 Lattice parameters of Bi impurity phase in $\text{La}_2\text{O}_2\text{Bi}$ ($x_{\text{Sr}} = 0.16, 0.20, x_{\text{Ba}} = 0.10, 0.20$). The longer a - and c - axis lengths for Ba doping were possibly due to the formation of Bi-Ba alloy.¹

	$x_{\text{Sr}} = 0.16$	$x_{\text{Sr}} = 0.20$	$x_{\text{Ba}} = 0.10$	$x_{\text{Ba}} = 0.20$
Phase	Bi	Bi	Bi	Bi
Space group	$R-3m$	$R-3m$	$R-3m$	$R-3m$
a (Å)	4.5508(18)	4.5506(13)	4.5548(12)	4.5504(4)
c (Å)	11.8404(77)	11.8438(49)	11.8586(52)	11.8677(18)

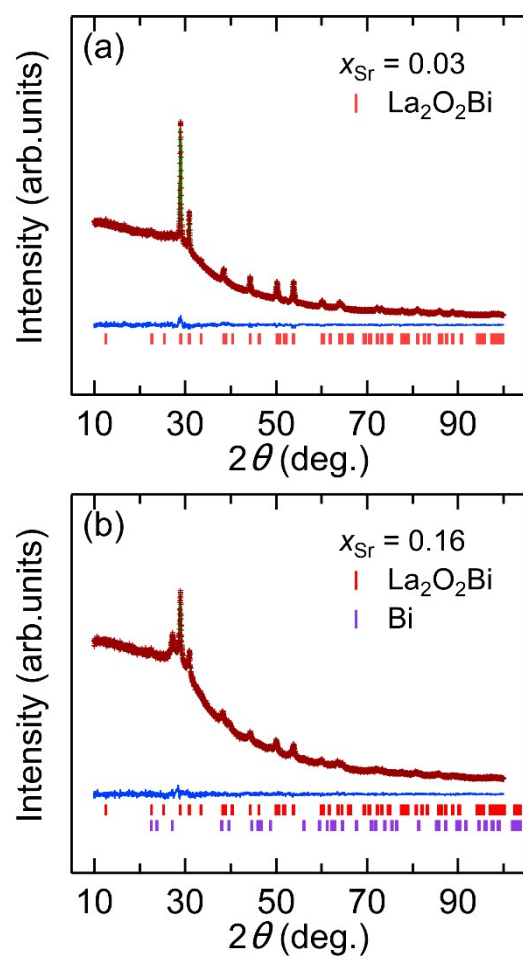


Fig. S1 XRD patterns and the fitting results of Rietveld refinement for (a) $x_{\text{Sr}} = 0.03$, and (b) $x_{\text{Sr}} = 0.16$. Brown, green, and blue curves denote the measurement data, simulation pattern, and their difference, respectively.

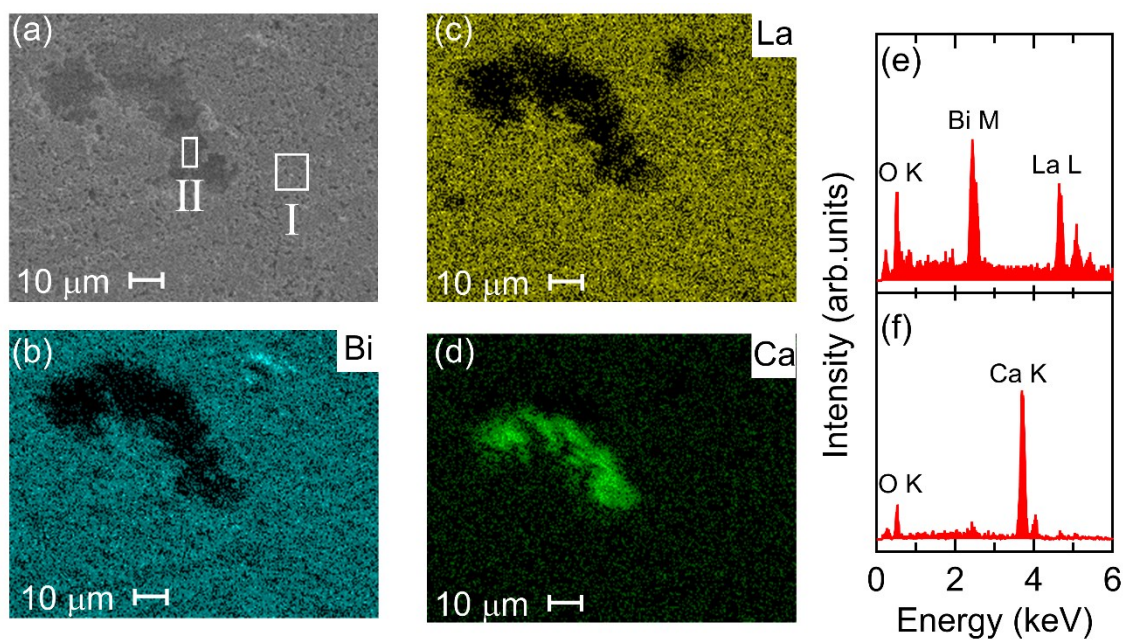


Fig. S2 (a) SEM image and the EDX mappings of (b) Bi, (c) La, (d) Ca for $\text{La}_2\text{O}_2\text{Bi}$ ($x_{\text{Ca}} = 0.20$). EDX spectra in the selected areas of (e) I and (f) II in (a). Ca was segregated locally, and La and Bi were distributed homogeneously.

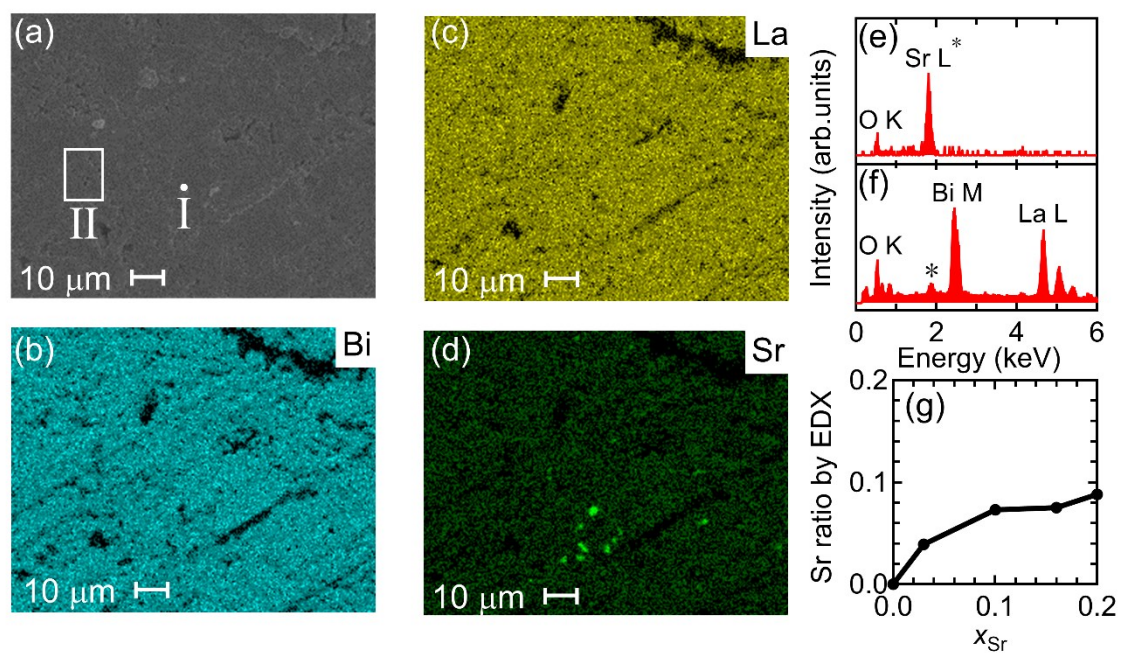


Fig. S3 (a) SEM image and the EDX mappings of (b) Bi, (c) La, (d) Sr for $\text{La}_2\text{O}_2\text{Bi}$ ($x_{\text{Sr}} = 0.10$). EDX spectra (e) at the point I on a SrO grain and (f) in the area II displayed in (a). Bi and La peaks were absent in (e) because only the SrO grain was excited by the point focused measurement.² (g) Sr substitution ratio calculated by $\text{Sr}/(\text{Sr} + \text{La})$ from EDX as a function of x_{Sr} . Sr was distributed almost homogeneously with a tiny segregation. The solubility limit of Sr was about 0.09.

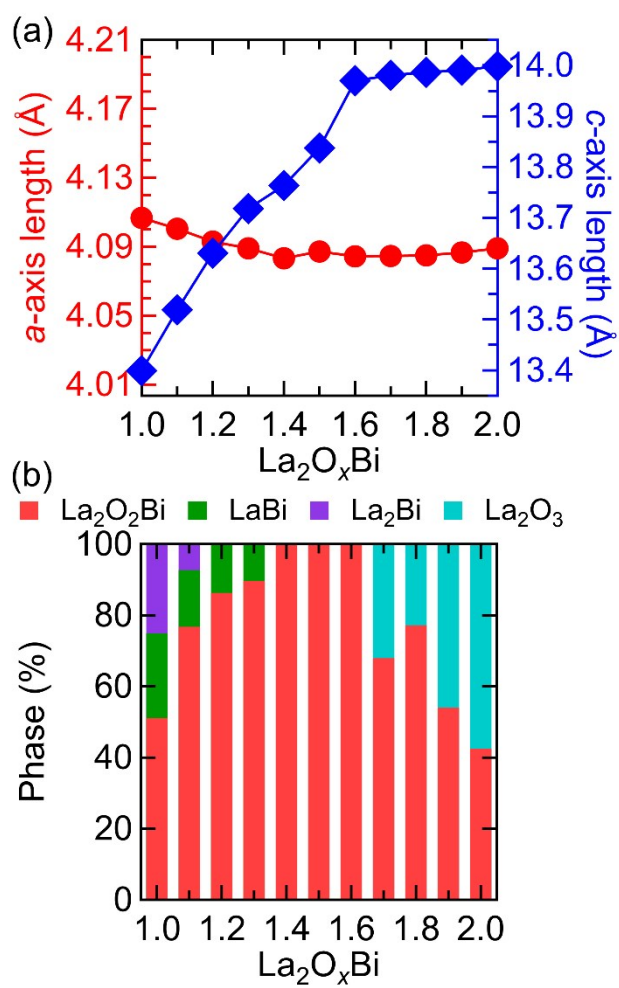


Fig. S4 (a) a - and c -axis lengths and (b) molar fractions of constituent phases for $\text{La}_2\text{O}_x\text{Bi}$ synthesized with different nominal composition.

Supplementary reference

- 1 T. Lichtenstein, N. D. Smith, J. Gesualdi, K. Kumar and H. Kim, *Electrochim. Acta*, 2017, **228**, 628–635.
- 2 J. I. Goldstein, C. E. Lyman, D. E. Newbury, E. Lifshin, P. Echlin, L. Sawyer, D. C. Joy and J. R. Michael, *Scanning Electron Microscopy and X-Ray Microanalysis*, Springer, New York, 3rd ed., 2003.